



## ATE Production Test Limit Evaluation

### Services Included:

- Prior to Start of Project
  - A kickoff meeting/conference call will be held to ensure good flow of information between the customer and WML engineers
  - A detailed project schedule will be provided outlining work to be done with milestones and dates
  - Customer provides existing production test program, load board, and device specification in addition to a large sample of packaged samples from wafer fab “corners lot” (~200/split)
  - A customized characterization test program is then developed to exercise the device over specified temperature range, voltage range and across process splits
- Data Collection
  - Test program is used to collect data on all devices at minimum, maximum and room temperature and across the full supply voltage range
  - All data is saved to disk and traceable back to process split, temperature and voltage
- Statistical Data Analysis
  - Specialized statistical analysis and reporting tools are used to parse the data and create a detailed graphical output of each test result (over all extremes of temperature, voltage and process variation)
- Final Summary
  - A wrap-up meeting is held to share all results from the characterization
  - A detailed characterization report is provided to the customer showing performance of each test over the full temperature range, voltage range and across all process splits
  - A final recommendations report is also provided outlining potential voltage or process sensitivities that could affect yield

### Deliverables:

- Detailed characterization report showing electrical performance of device over temperature, voltage and process variation
- Final recommendations report outlining potential temperature, voltage or process sensitivities that could affect product yield in production

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